



40V COMPLEMENTARY PAIR ENHANCEMENT MODE MOSFET

Product Summary

			I _D Max
Device	V _{(BR)DSS}	R _{DS(ON)} Max	T _A = +25°C
			(Notes 6 & 8)
Q1	40V	45mΩ @ V _{GS} = 10V	5.5A
QT	400	60mΩ @ V _{GS} = 4.5V	4.2A
Q2	40\/	45mΩ @ V _{GS} = -10V	-5.8A
QZ	-40V	60mΩ @ V _{GS} = -4.5V	-4.2A

Description

This MOSFET is designed to ensure that R_{DS(ON)} of N and P channel FET are matched to minimize losses in both arms of the bridge. The DMC4040SSD is optimized for use in 3-phase brushless DC motor circuits (BLDC), and CCFL backlighting.

Applications

- 3-Phase BLDC Motor
- CCFL Backlighting

Features and Benefits

- Matched N & P R_{DS(ON)} Minimizes Power Losses •
- Fast Switching Minimizes Switching Losses •
- Dual Device Reduces PCB Area
- Totally Lead-Free & Fully RoHS Compliant (Notes 1 & 2)
- Halogen and Antimony Free. "Green" Device (Note 3)

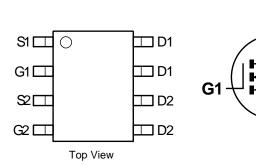
Mechanical Data

- Case: SO-8
- Case Material: Molded Plastic, "Green" Molding Compound. UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020

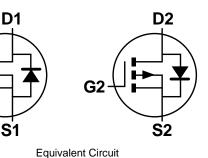
S1

- Terminals: Finish Matte Tin Annealed over Copper Leadframe. . Solderable per MIL-STD-202, Method 208 @3
- Weight: 0.074 grams (Approximate)

Top View



SO-8



Ordering Information (Note 4)

Product	Marking	Reel Size (inches)	Tape Width (mm)	Quantity per Reel	
DMC4050SSD-13 C4050SD		13	12	2,500	
Notes: 1. No purposely added lead. Fully EU Directive 2002/95/EC (RoHS) & 2011/65/EU (RoHS 2) compliant.					

1. No purposely added lead. Fully EU Directive 2002/95/EC (RoHS) & 2011/65/EU (RoHS 2) compliant.

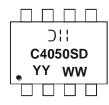
2. See http://www.diodes.com/quality/lead_free.html for more information about Diodes Incorporated's definitions of Halogen- and Antimony-free, "Green" and Lead-free.

3. Halogen- and Antimony-free "Green" products are defined as those which contain <900ppm bromine, <900ppm chlorine (<1500ppm total Br + Cl) and <1000ppm antimony compounds.

4. For packaging details, go to our website at http://www.diodes.com/products/packages.html.



Marking Information



)'' = Manufacturer's Marking C4050SD = Product Type Marking Code YYWW = Date Code Marking YY or \overline{YY} = Year (ex: 10 = 2010) WW = Week (01 - 53)

Maximum Ratings (@T_A = +25°C, unless otherwise specified.)

Characteristic			Symbol	N-Channel - Q1	P-Channel - Q2	Units
Drain-Source Voltage			V _{DSS}	40	-40	N/
Gate-Source Voltage			V _{GSS}	±20	±20	v
Continuous Drain Current V _{GS} = 1		(Notes 6 & 8)		5.8	-5.8	A
	V _{GS} = 10V	T _A = +70°C (Notes 6 & 8)	Ι _D	4.38	-4.52	
		(Notes 5 & 8)		4.2	-4.2	
		(Notes 5 & 9)		5.3	-5.3	
Pulsed Drain Current	$V_{GS} = 10V$	(Notes 7 & 8)	I _{DM}	24.1	-24.9	
Continuous Source Current (Body Diode)		(Notes 6 & 8)	Is	2.5	-2.5	
Pulsed Source Current (Body Diode)		(Notes 7 & 8)	I _{SM}	24.1	-24.9	

Thermal Characteristics

Characteristic		Symbol	N-Channel - Q1 P-Channel - Q2	Unit	
Dever Dissingtion	(Notes 5 & 8)		1.25 10		
Power Dissipation Linear Derating Factor	(Notes 5 & 9)	PD	1.8 14.3	W mW/°C	
	(Notes 6 & 8)		2.14 17.2		
	(Notes 5 & 8)		100	°C/W	
Thermal Resistance, Junction to Ambient	(Notes 5 & 9)	R _{0JA}	70		
	(Notes 6 & 8)		58		
Thermal Resistance, Junction to Lead	(Notes 5 & 10)	R _{θJL}	51		
Operating and Storage Temperature Range		TJ. TSTG	-55 to +150	°C	

Notes: 5. For a device surface mounted on 25mm x 25mm x 1.6mm FR4 PCB with high coverage of single sided 1oz copper, in still air conditions; the device is measured when operating in a steady-state condition.

6. Same as note (5), except the device is measured at t \leq 10 sec.

7. Same as note (5), except the device is pulsed with D = 0.02 and pulse width 300 μ s.

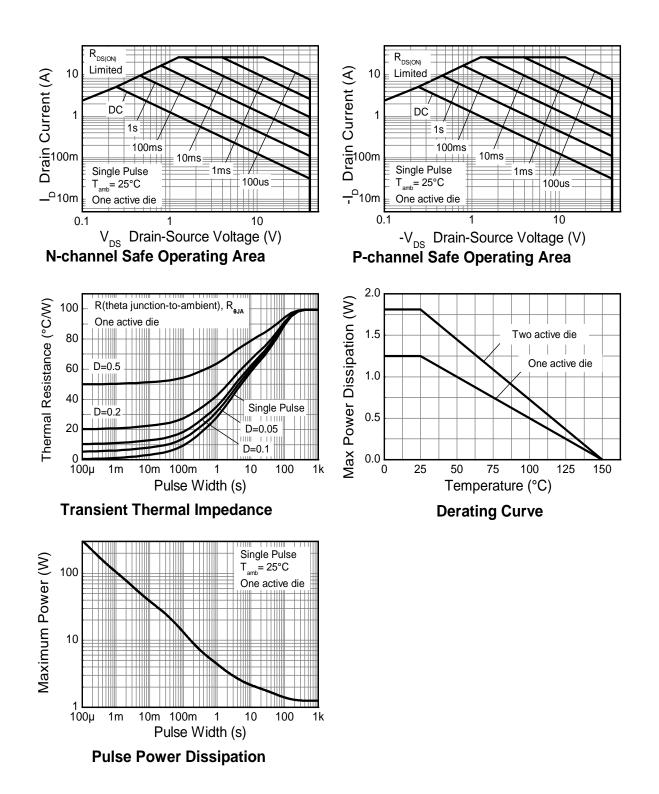
8. For a dual device with one active die.

9. For a device with two active die running at equal power.

10. Thermal resistance from junction to solder-point (at the end of the drain lead).



Thermal Characteristics (Continued)





Electrical Characteristics (Q1 N-Channel) (@T_A = +25°C, unless otherwise specified.)

Characteristic	Symbol	Min	Turn	Max	Unit	Test Condition
OFF CHARACTERISTICS (Note 11)	Symbol	IVIIII	Тур	IVIAX	Unit	Test condition
Drain-Source Breakdown Voltage	BV _{DSS}	40	_	_	V	$V_{GS} = 0V, I_{D} = 250 \mu A$
Zero Gate Voltage Drain Current $T_J = +25^{\circ}C$	I _{DSS}		_	1.0	μA	$V_{DS} = 40V, V_{GS} = 0V$
Gate-Source Leakage	I _{GSS}	_	—	±100	nA	$V_{GS} = \pm 20V, V_{DS} = 0V$
ON CHARACTERISTICS (Note 11)						÷
Gate Threshold Voltage	V _{GS(th)}	0.8	1.3	1.8	V	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$
Static Drain-Source On-Resistance			20	45	mΩ	$V_{GS} = 10V, I_D = 3A$
	R _{DS(ON)}	_	33	60	11152	$V_{GS} = 4.5V$, $I_D = 3A$
Forward Transfer Admittance	Y _{fs}	_	12.6	_	S	$V_{DS} = 5V, I_D = 3A$
Diode Forward Voltage (Note 11)	V _{SD}	—	0.7	1.0	V	$V_{GS} = 0V, I_S = 1A$
DYNAMIC CHARACTERISTICS (Note 12)						
Input Capacitance	Ciss	_	1790.8		pF	
Output Capacitance	C _{oss}	—	160.6		pF	$V_{DS} = 20V, V_{GS} = 0V,$ - f = 1.0MHz
Reverse Transfer Capacitance	C _{rss}	—	120.5	_	pF	1 - 1.00012
Gate Resistance	Rg	_	1.03		Ω	$V_{DS} = 0V, V_{GS} = 0V, f = 1MHz$
Total Gate Charge	Qg	—	37.56		nC	V 10V V 20V
Gate-Source Charge	Q _{gs}	_	7.8	_	nC	− V _{GS} = 10V, V _{DS} = 20V, − I _D = 3A
Gate-Drain Charge	Q _{gd}	—	6.6	_	nC	ID = SR
Turn-On Delay Time	t _{D(on)}	_	8.08	_	nS	
Turn-On Rise Time	tr	_	15.14		nS	$V_{GS} = 10V, V_{DS} = 20V,$
Turn-Off Delay Time	t _{D(off)}	_	24.29	_	nS	$I_D = 3A$
Turn-Off Fall Time	t _f	_	5.27	_	nS	

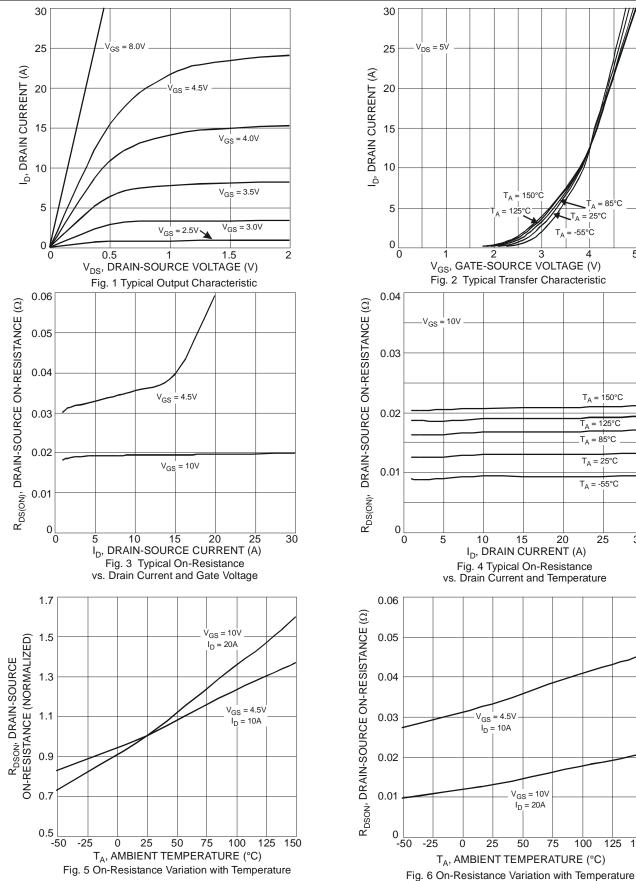
Electrical Characteristics (Q2 P-Channel) (@T_A = +25°C, unless otherwise specified.)

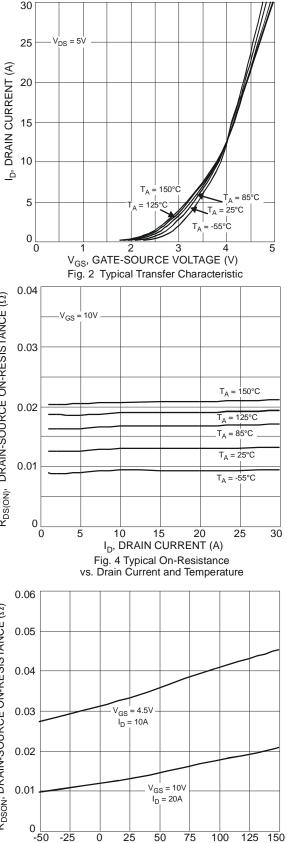
Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition	
OFF CHARACTERISTICS (Note 11)						-	
Drain-Source Breakdown Voltage	BV _{DSS}	-40	—		V	$V_{GS} = 0V, I_D = -250\mu A$	
Zero Gate Voltage Drain Current T _J = +25°C	I _{DSS}	_	—	-1.0	μA	$V_{DS} = -40V, V_{GS} = 0V$	
Gate-Source Leakage	I _{GSS}	—	—	±100	nA	$V_{GS} = \pm 20V, V_{DS} = 0V$	
ON CHARACTERISTICS (Note 11)							
Gate Threshold Voltage	V _{GS(th)}	-0.8	-1.3	-1.8	V	$V_{DS} = V_{GS}, I_D = -250 \mu A$	
Static Drain-Source On-Resistance	P		28	45	mΩ	$V_{GS} = -10V, I_D = -3A$	
Static Drain-Source On-Resistance	R _{DS(ON)}		30	60	11152	$V_{GS} = -4.5V, I_D = -3A$	
Forward Transfer Admittance	Y _{fs}	—	16.6		S	$V_{DS} = -5V, I_D = -3A$	
Diode Forward Voltage (Note 11)	V _{SD}	—	-0.7	-1.0	V	$V_{GS} = 0V, I_{S} = -1A$	
DYNAMIC CHARACTERISTICS (Note 12)							
Input Capacitance	C _{iss}	—	1643.17		pF		
Output Capacitance	C _{oss}	_	179.13	_	pF	$V_{DS} = -20V, V_{GS} = 0V,$ - f = 1.0MHz	
Reverse Transfer Capacitance	Crss	—	127.82		pF	1 - 1.00012	
Gate Resistance	R _g	—	6.43		Ω	$V_{DS} = 0V, V_{GS} = 0V, f = 1MHz$	
Total Gate Charge	Qg	—	33.66		nC	101/1/ 201/	
Gate-Source Charge	Q _{gs}	—	5.54		nC	$V_{GS} = -10V, V_{DS} = -20V,$ $I_{D} = -3A$	
Gate-Drain Charge	Q_{gd}	_	7.30		nC	$I_D = -3A$	
Turn-On Delay Time	t _{D(on)}	_	6.85		nS		
Turn-On Rise Time	tr	_	14.72		nS	$V_{GS} = -10V, V_{DS} = -20V,$	
Turn-Off Delay Time	t _{D(off)}	_	53.65		nS	I _D = -3A	
Turn-Off Fall Time	t _f	_	30.86		nS		

 Short duration pulse test used to minimize self-heating effect.
Guaranteed by design. Not subject to production testing. Notes:



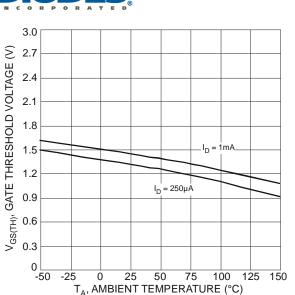
Typical Characteristics (Q1 N-Channel)



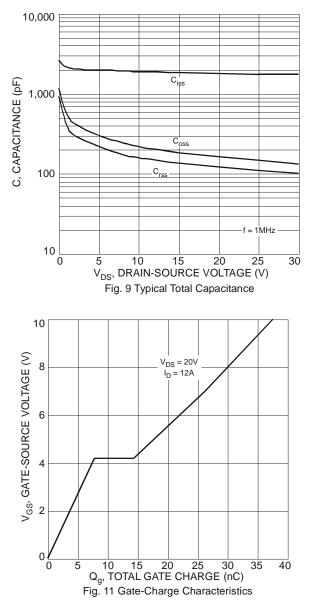


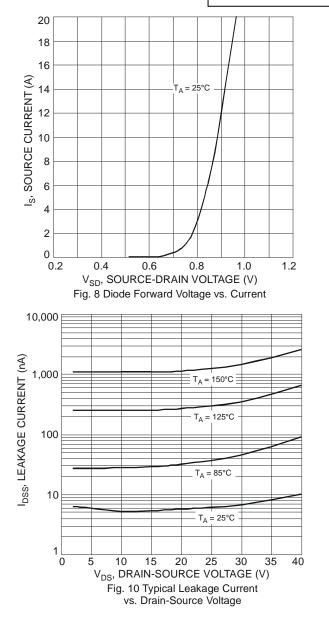
DMC4050SSD Document number: DS33310 Rev. 3 - 2





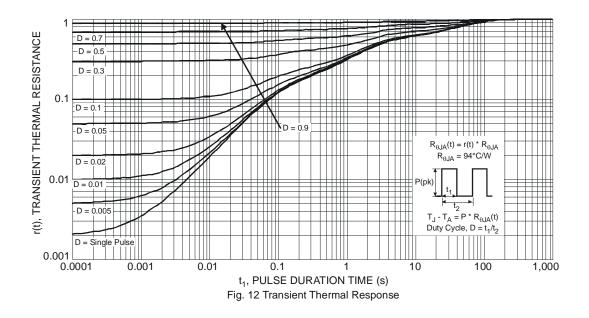






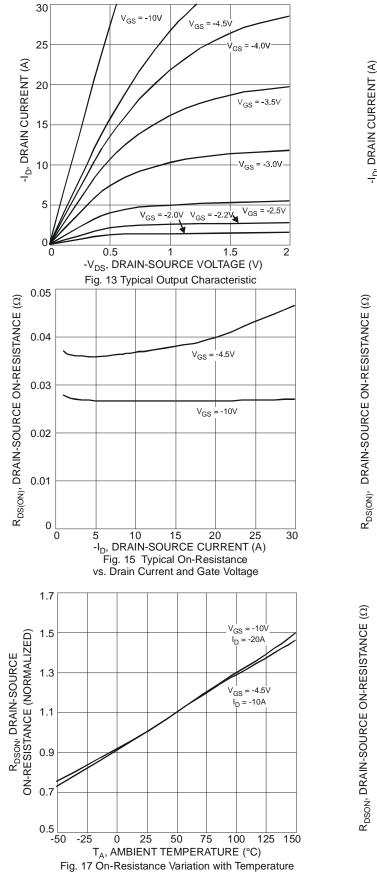
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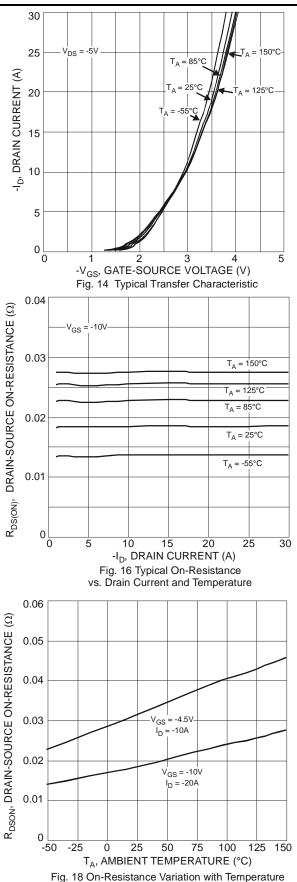






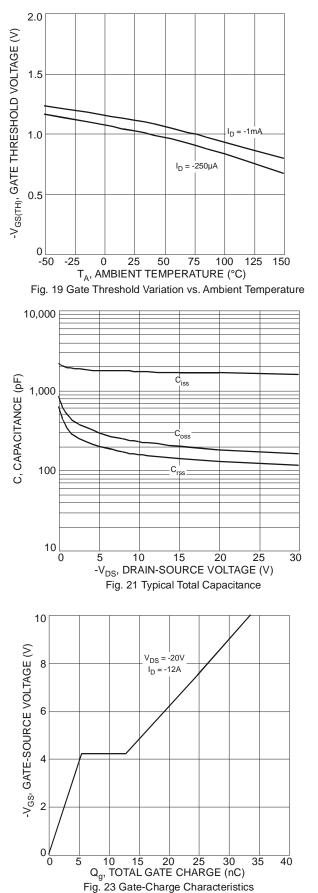
Typical Characteristics (Q2 P-Channel)

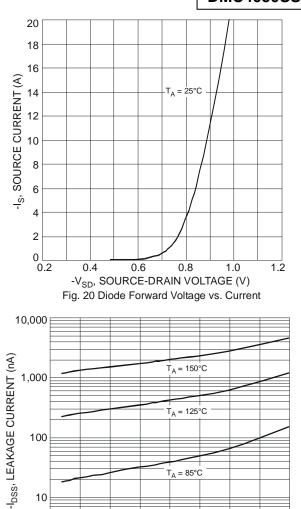


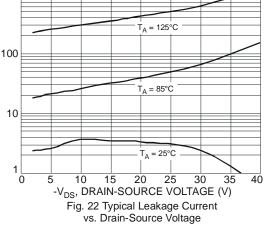




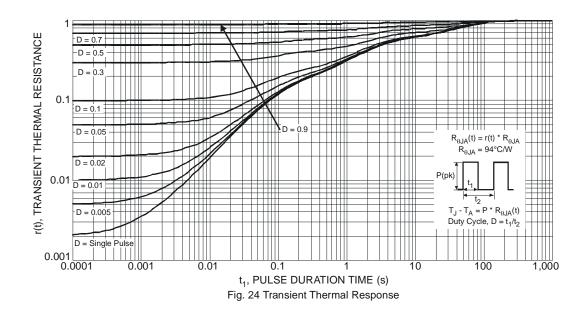










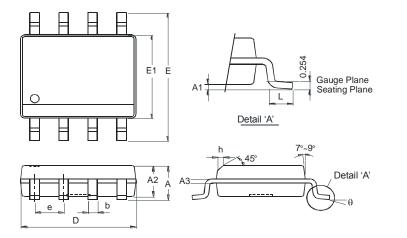




Package Outline Dimensions

Please see AP02002 at http://www.diodes.com/datasheets/ap02002.pdf for the latest version.

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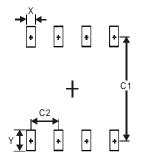


	SO-8				
Dim	Min	Max			
Α	-	1.75			
A1	0.10	0.20			
A2	1.30	1.50			
A3	0.15	0.25			
b	0.3	0.5			
D	4.85	4.95			
Е	5.90	6.10			
E1	3.85	3.95			
е	1.27 Typ				
h	-	0.35			
L	0.62	0.82			
θ	0° 8°				
All Dimensions in mm					

Suggested Pad Layout

Please see AP02001 at http://www.diodes.com/datasheets/ap02001.pdf for the latest version.

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Dimensions	Value (in mm)
Х	0.60
Y	1.55
C1	5.4
C2	1.27



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